

	Type	L #	Hits	Search Text	DBs	Time Stamp
1	IS&R	L1	8	((("5612548") or ("5541423") or ("5500539") or ("5347147") or ("5034784jp04240784"))).PN.	USPAT; EPO; JPO; DERWEN T; IBM_TD B	2004/02/13 08:47
2	IS&R	L2	10	((("5612548") or ("5541423") or ("5500539") or ("5347147") or ("5034784") or ("jp4240784"))).PN.	USPAT; EPO; JPO; DERWEN T; IBM_TD B	2004/02/13 09:42
3	IS&R	L3	0	("jp4240784").PN.	USPAT; EPO; JPO; DERWEN T; IBM_TD B	2004/02/13 09:42
4	IS&R	L4	0	("jp-4240784").PN.	USPAT; EPO; JPO; DERWEN T; IBM_TD B	2004/02/13 09:43
5	BRS	L5	2	jp-04240784-\$.did.	USPAT; EPO; JPO; DERWEN T; IBM_TD B	2004/02/13 09:43

	Type	L #	Hits	Search Text	DBs	Time Stamp
1	BRS	L1	29583	diamond and (free exciton)	USPAT; EPO; JPO; DERWEN T; IBM_TD B	2004/02/13 07:01
2	BRS	L2	13342	1 and light	USPAT; EPO; JPO; DERWEN T; IBM_TD B	2004/02/13 06:59
3	BRS	L3	1616	1 and (light adj emitt\$4)	USPAT; EPO; JPO; DERWEN T; IBM_TD B	2004/02/13 06:59
4	BRS	L4	1216	1 and (light adj (emitter emitting))	USPAT; EPO; JPO; DERWEN T; IBM_TD B	2004/02/13 06:59
5	BRS	L5	280	4 and (257/\$.ccls. 372/\$.ccls.)	USPAT; EPO; JPO; DERWEN T; IBM_TD B	2004/02/13 07:00
6	BRS	L6	8	diamond and (free adj exciton)	USPAT; EPO; JPO; DERWEN T; IBM_TD B	2004/02/13 07:01

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore[®]

RELEASE 1.6

Welcome
United States Patent and Trademark Office

Help FAQ Terms IEEE Peer Quick Links

Review

Welcome to IEEE Xplore

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

Your search matched **2** of **1003743** documents.

A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering new one in the text box.

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

1 Diamond radiation sensors for medical applications

Blum, F.; Denisenko, A.; Job, R.; Borchert, D.; Fahrner, W.R.;

Industrial Electronics, 1998. Proceedings. ISIE '98. IEEE International Symposium on , Volume: 1 , 7-10 July 1998

Pages:163 - 166 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(344 KB\)\]](#) **IEEE CNF**

2 Nuclear radiation detectors on various type diamonds

Blum, F.; Denisenko, A.; Job, R.; Borchert, D.; Weber, W.; Borany, J.V.;

Hilleringmann, U.; Fahrner, W.R.;

Industrial Electronics Society, 1998. IECON '98. Proceedings of the 24th Annual Conference of the IEEE , Volume: 4 , 31 Aug.-4 Sept. 1998

Pages:2382 - 2385 vol.4

[\[Abstract\]](#) [\[PDF Full-Text \(364 KB\)\]](#) **IEEE CNF**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#)
| [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

?show files

File 2:INSPEC 1969-2004/Feb W1
(c) 2004 Institution of Electrical Engineers
File 6:NTIS 1964-2004/Feb W2
(c) 2004 NTIS, Intl Cpyrght All Rights Res
File 8:Ei Compendex(R) 1970-2004/Feb W1
(c) 2004 Elsevier Eng. Info. Inc.
File 25:Weldasearch 1966-2002/Aug
(c) 2004 TWI Ltd
File 34:SciSearch(R) Cited Ref Sci 1990-2004/Feb W2
(c) 2004 Inst for Sci Info
File 65:Inside Conferences 1993-2004/Feb W2
(c) 2004 BLDSC all rts. reserv.
File 92:IHS Intl.Stds.& Specs. 1999/Nov
(c) 1999 Information Handling Services
File 94:JICST-EPlus 1985-2004/Feb W1
(c)2004 Japan Science and Tech Corp(JST)
File 95:TEME-Technology & Management 1989-2004/Jan W4
(c) 2004 FIZ TECHNIK
File 99:Wilson Appl. Sci & Tech Abs 1983-2004/Jan
(c) 2004 The HW Wilson Co.
File 103:Energy SciTec 1974-2004/Feb B1
(c) 2004 Contains copyrighted material
File 144:Pascal 1973-2004/Feb W1
(c) 2004 INIST/CNRS
File 239:Mathsci 1940-2004/Mar
(c) 2004 American Mathematical Society
File 241:Elec. Power DB 1972-1999Jan
(c) 1999 Electric Power Research Inst.Inc
File 434:SciSearch(R) Cited Ref Sci 1974-1989/Dec
(c) 1998 Inst for Sci Info
File 647:CMP Computer Fulltext 1988-2004/Feb W1
(c) 2004 CMP Media, LLC

?ds

Set	Items	Description
S1	17	DIAMOND AND (FREE EXCITON)
?		

09949010 Genuine Article#: 468UQ Number of References: 23

Title: Efficient free-exciton recombination emission from diamond diode at room temperature

Author(s): Horiuchi K (REPRINT) ; Kawamura A; Ide T; Ishikura T; Takamura K ; Yamashita S

Corporate Source: Tokyo Gas Co Ltd, Dept Res & Dev, Frontier Technol Lab, Tsurumi Ku, 1-7-7 Suehiro Cho/Yokohama/Kanagawa 2300045/Japan/ (REPRINT) ; Tokyo Gas Co Ltd, Dept Res & Dev, Frontier Technol Lab, Tsurumi Ku, Yokohama/Kanagawa 2300045/Japan/

Journal: JAPANESE JOURNAL OF APPLIED PHYSICS PART 2-LETTERS, 2001, V40, N3B (MAR 15), PL275-L278

ISSN: 0021-4922 Publication date: 20010315

Publisher: INST PURE APPLIED PHYSICS, DAINI TOYOKAIJI BLDG, 4-24-8

SHINBASHI, MINATO-KU TOKYO, 105-004, JAPAN

Language: English Document Type: ARTICLE

Geographic Location: Japan

Journal Subject Category: PHYSICS, APPLIED

Abstract: Free-exciton recombination emission of 235 nm in wavelength is obtained by current injection at room temperature from a **diamond**-based pn junction diode composed of B-doped crystal grown by high-temperature, high-pressure synthesis and a S-doped homoepitaxial layer grown by the chemical vapor deposition method. The diode shows a clear rectification characteristic and a high external quantum efficiency of excitonic emission, 8×10^{-5} , which indicates that the excitonic emission of **diamond** is a good candidate for application to semiconductor UV-light-emitting devices. A defect-induced light emission and large leakage current indicate that a higher UV emission efficiency is expected with improvement of the junction quality.

Descriptors--Author Keywords: **diamond** ; UV ; light-emitting diode ; **free exciton** ; electroluminescence ; sulfur-doping ; n-type conductivity

Identifiers--KeyWord Plus(R): CHEMICAL-VAPOR-DEPOSITION; THIN-FILM; ELECTROLUMINESCENCE; SULFUR

Cited References: